

ABSTRACT

A digital imaging method, in which the object being imaged is irradiated and the radiation is directed by means of semiconductor sensors (1), covering an area which is smaller than the image-forming surface. The semiconductor sensors (1) are arranged in such a way that the image-forming surface can be imaged in two irradiations by moving the semiconductor sensors (1) between the irradiations. The radiation can be limited to the area covered by the sensors (1) by means of collimators (4). The semiconductor sensors (1) are arranged to form advantageously rectangular bars (2), which comprise several semiconductor sensors (1) in the form of one or two columns, in which the bars (2) are arranged advantageously at a distance from one another, the distance between the bars being at most equal to the width of the active area of the semiconductor sensors of the bars.